



Description

The HXY40P02D uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = -20V$ $I_D = -40A$

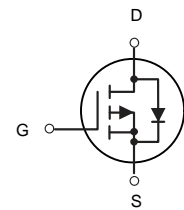
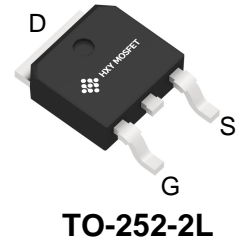
$R_{DS(ON)} < 18 m\Omega$ @ $V_{GS} = -4.5V$

Application

Battery protection

Load switch

Uninterruptible power supply



P-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
HXY40P02D	TO-252-2L	HXY MOSFET	2500

Absolute Maximum Ratings ($T_A = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	-20	V
V_{GS}	Gate-Source Voltage	± 12	V
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ -10V$	-40	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ -10V$	-15.7	A
I_{DM}	Pulsed Drain Current	-66	A
EAS	Single Pulse Avalanche Energy	28.8	mJ
I_{AS}	Avalanche Current	-26.6	A
$P_D @ T_C = 25^\circ C$	Total Power Dissipation	30	W
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ C$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient	41.6	$^\circ C/W$



Electrical Characteristics (T_A=25°C unless otherwise note d)

Parameter		Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Static Characteristics							
Drain-Source Breakdown Voltage		V _{(BR)DSS}	V _{GS} = 0V, I _D = -250μA	-20	-	-	V
Gate-body Leakage current		I _{GSS}	V _{DS} = 0V, V _{GS} = ±12V	-	-	±100	nA
Zero Gate Voltage Drain Current	T _J = 25°C	I _{DSS}	V _{DS} = -20V, V _{GS} = 0V	-	-	-1	μA
	T _J = 100°C			-	-	-100	
Gate-Threshold Voltage		V _{GS(th)}	V _{DS} = V _{GS} , I _D = -250μA	-0.4	-0.65	-1	V
Drain-Source On-Resistance ⁴		R _{DS(on)}	V _{GS} = -4.5V, I _D = -8A	-	12.0	18	mΩ
			V _{GS} = -2.5V, I _D = -6A	-	17	23	
Forward Transconductance ⁴		g _{fs}	V _{DS} = -4.5V, I _D = -8A	-	36	-	S
Dynamic Characteristics ⁵							
Input Capacitance		C _{iss}	V _{DS} = -10V, V _{GS} = 0V, f = 1MHz	-	1630	-	pF
Output Capacitance		C _{oss}		-	211	-	
Reverse Transfer Capacitance		C _{rss}		-	187	-	
Gate Resistance		R _g	f = 1MHz	-	10	-	Ω
Switching Characteristics ⁵							
Total Gate Charge		Q _g	V _{GS} = -4.5V, V _{DS} = -10V, I _D = -8A	-	12	-	nC
Gate-Source Charge		Q _{gs}		-	1.8	-	
Gate-Drain Charge		Q _{gd}		-	3.2	-	
Turn-On Delay Time		t _{d(on)}	V _{GS} = -4.5V, V _{DD} = -10V, R _G = 3Ω, I _D = -8A	-	17	-	ns
Rise Time		t _r		-	25.5	-	
Turn-Off Delay Time		t _{d(off)}		-	32	-	
Fall Time		t _f		-	15	-	
Drain-Source Body Diode Characteristics							
Diode Forward Voltage ⁴		V _{SD}	I _S = -8A, V _{GS} = 0V	-	-	-1.2	V
Continuous Source Current	T _A = 25°C	I _S	-	-	-	-40	A

Notes:

1. Repetitive rating, pulse width limited by junction temperature T_{J(MAX)}=150°C.
2. The EAS data shows Max. rating . The test condition is V_{DD}= -25V, V_{GS}= -10V, L= 0.1mH, I_{AS}= -24A
3. The data tested by surface mounted on a 1 inch2 FR-4 board with 20Z copper, The value in any given application depends on the user's specific board design.
4. The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%.
5. This value is guaranteed by design hence it is not included in the production test..



Typical Characteristics

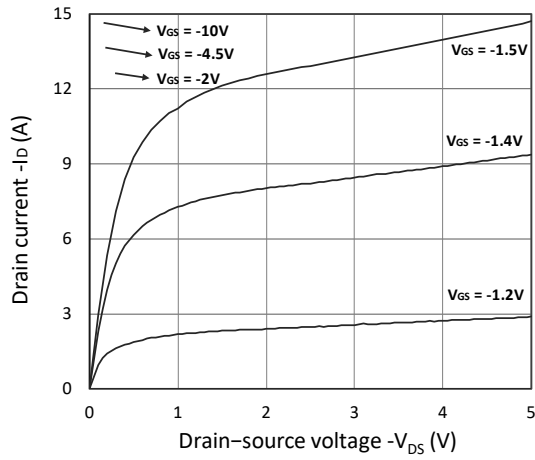


Figure 1. Output Characteristics

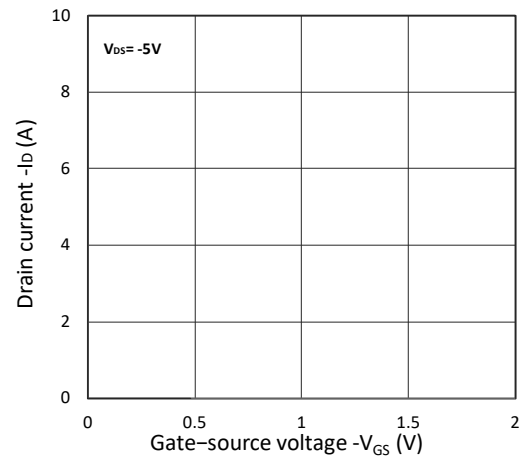


Figure 2. Transfer Characteristics

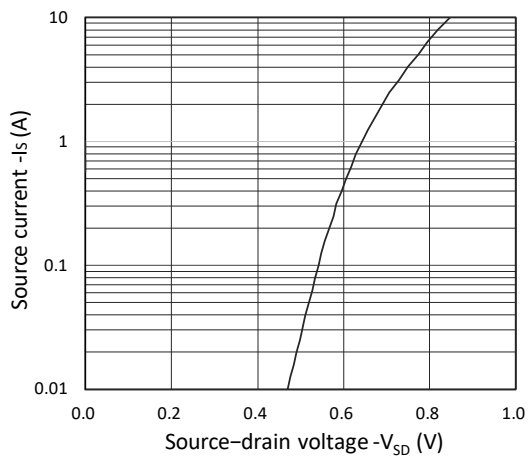


Figure 3. Forward Characteristics of Reverse

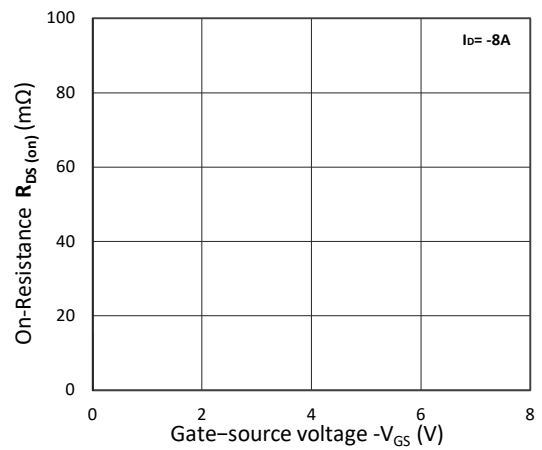


Figure 4. $R_{DS(on)}$ vs. V_{GS}

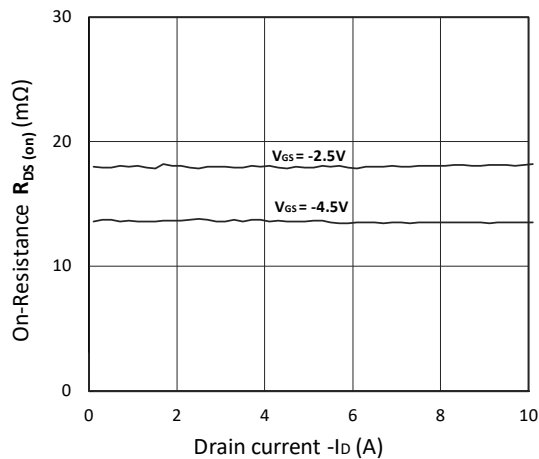


Figure 5. $R_{DS(on)}$ vs. I_D

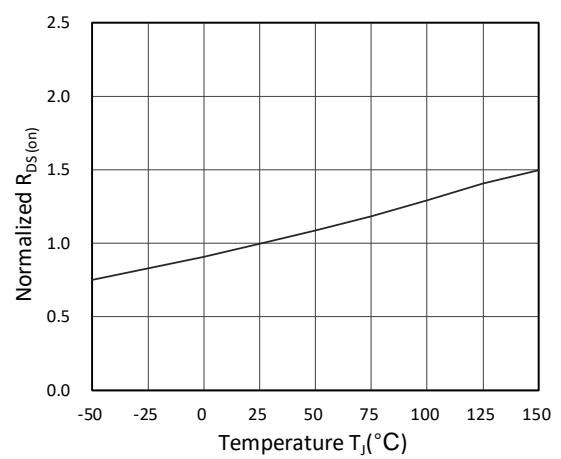


Figure 6. Normalized $R_{DS(on)}$ vs. Temperature

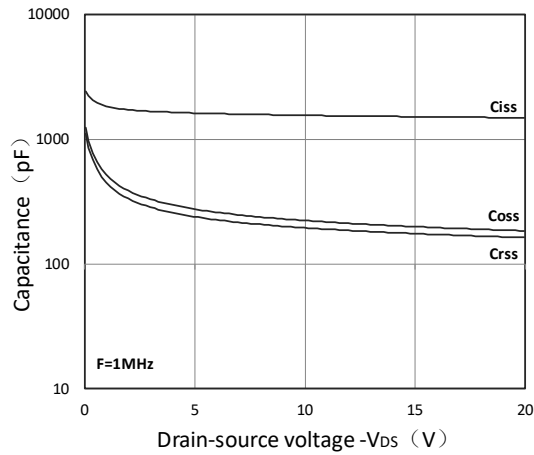


Figure 7. Capacitance Characteristics

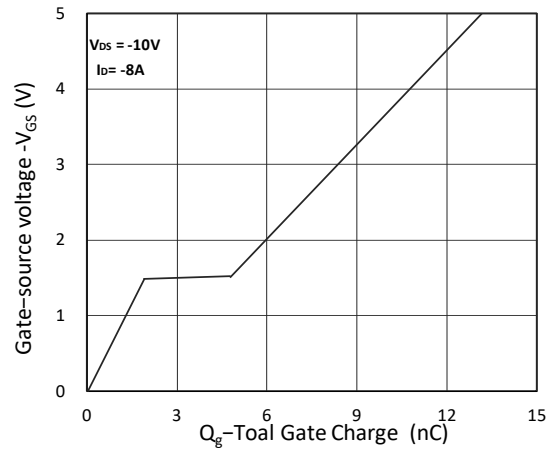


Figure 8. Gate Charge Characteristics

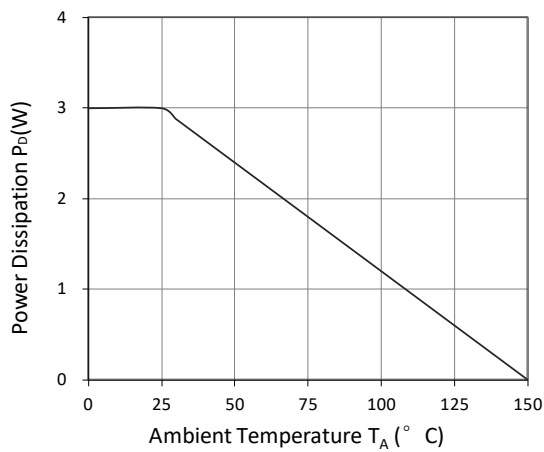


Figure 9. Power Dissipation

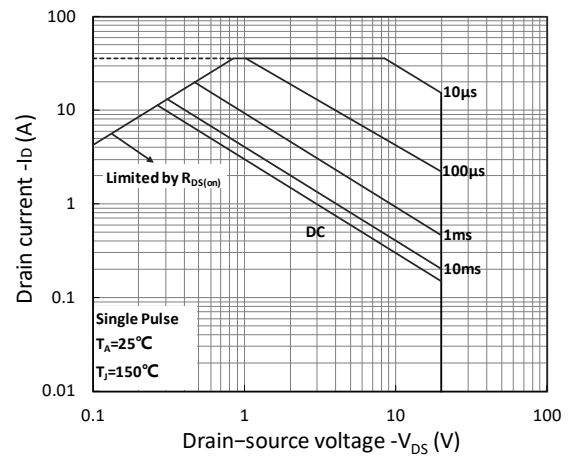


Figure 10. Safe Operating Area

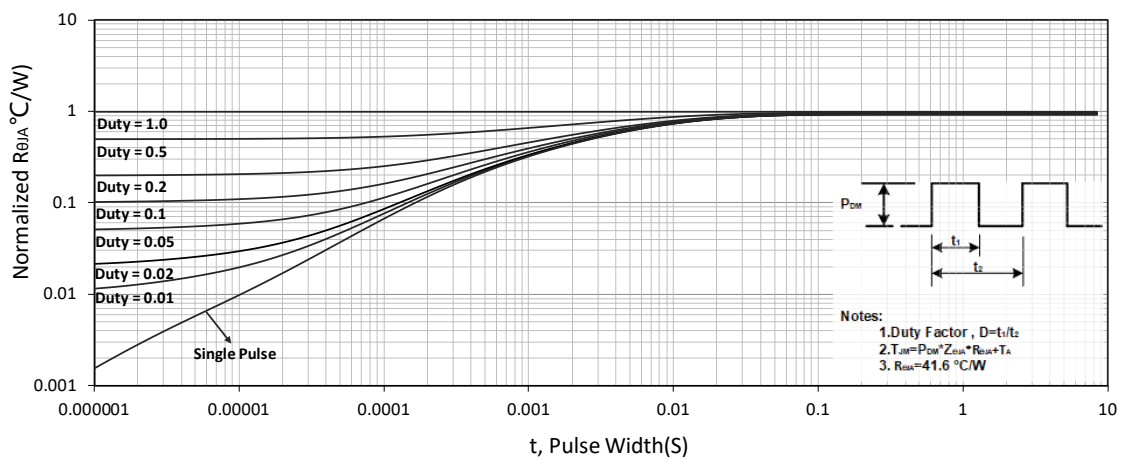
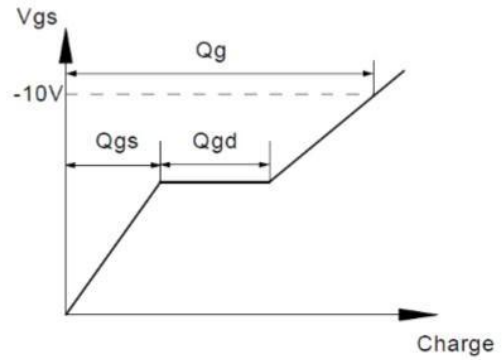
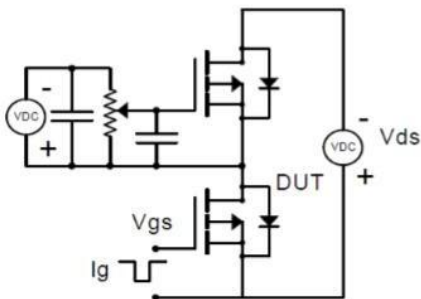


Figure 11. Normalized Maximum Transient Thermal Impedance

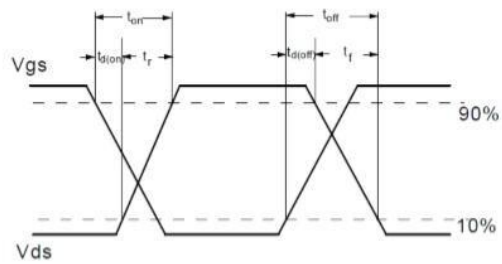
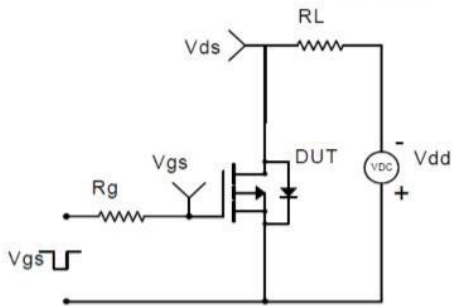


Test Circuit

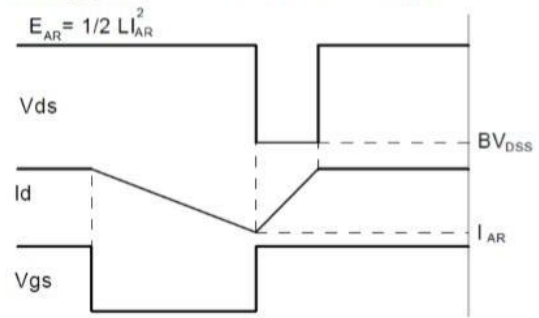
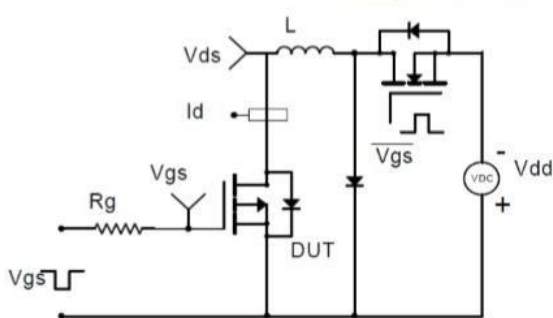
Gate Charge Test Circuit & Waveform



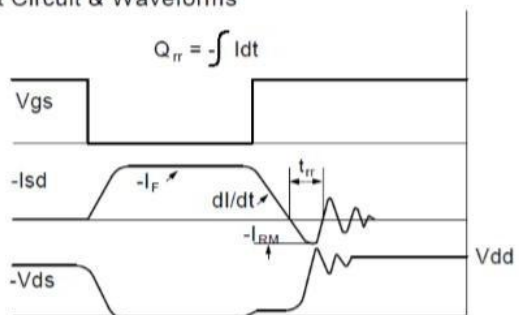
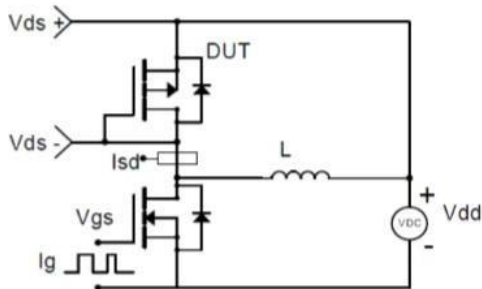
Resistive Switching Test Circuit & Waveforms



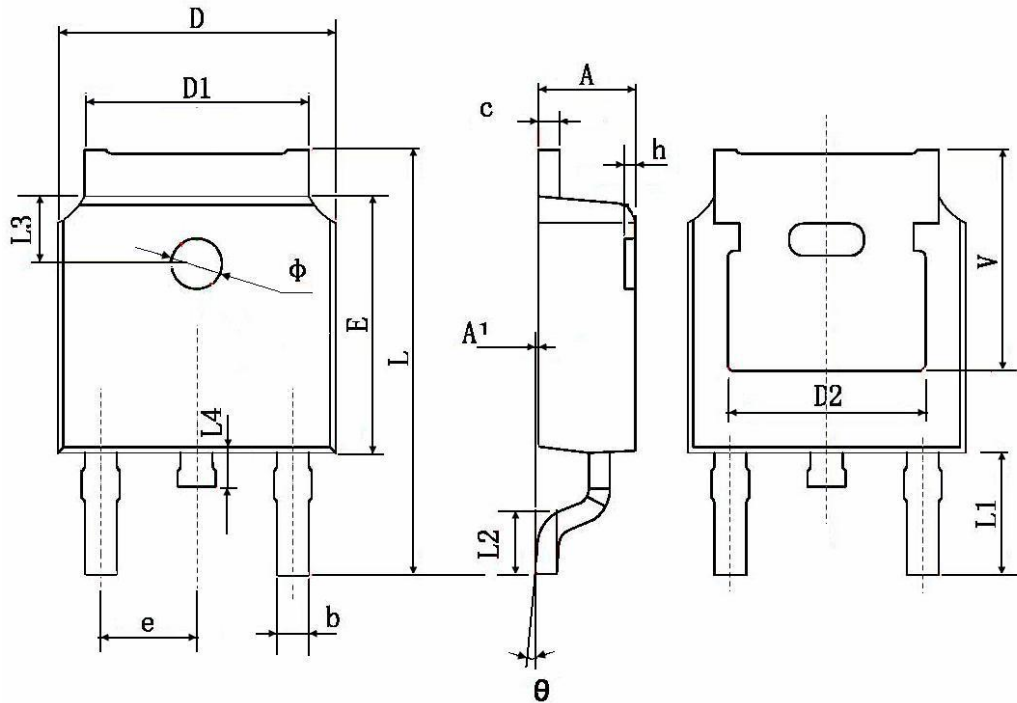
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



TO-252-2L Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.660	0.860	0.026	0.034
c	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	0.483 TYP.		0.190 TYP.	
E	6.000	6.200	0.236	0.244
e	2.186	2.386	0.086	0.094
L	9.800	10.400	0.386	0.409
L1	2.900 TYP.		0.114 TYP.	
L2	1.400	1.700	0.055	0.067
L3	1.600 TYP.		0.063 TYP.	
L4	0.600	1.000	0.024	0.039
Φ	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.350 TYP.		0.211 TYP.	



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